

MAR 02 2004

SHEET 1 OF 1

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
TRADEMARK AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT

ATTY DOCKET NO.
246244US2SRDSERIAL NO.
10/726,606

APPLICANT

Masato KOYAMA, et al.

FILING DATE
December 4, 2003

GROUP

2811

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
Vb	AA	6,613,658	09/02/2003	M. KOYAMA, et al.	438	591	—
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

✓ ✓	AW	C. S. KANG, et al., Applied Physics Letters, vol. 81, no. 14, pages 2593-2595, "BONDING STATES AND ELECTRICAL PROPERTIES OF ULTRATHIN HfO _x Ny GATE DIELECTRICS", September 30, 2002
✓ ✓	AX	M. R. VISOKAY, et al., Applied Physics Letters, vol. 80, no. 17, pages 3183-3185, "APPLICATION OF HfSiON AS A GATE DIELECTRIC MATERIAL", April 29, 2002
✓ ✓	AY	A. KANEKO, et al., Extended Abstracts of the 2002 International Conference on Solid State Devices and Materials, pages 742-743, "PLASMA NITRIDATION TECHNIQUE FOR THE FORMATION OF THERMALLY STABLE Hf-SILICATE GATE DIELECTRIC WITH CONTROLLED NITROGEN PROFILE", 2002

 Additional References sheet(s) attached

Examiner

HUNG VU

Date Considered

2/11/05

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.